


<b>Search Notes</b>  	<b>Application/Control No.</b>  10061982	<b>Applicant(s)/Patent Under Reexamination</b>  KUTARAGI ET AL.
	<b>Examiner</b>  Cloud, Joiya M	<b>Art Unit</b>  2144

SEARCHED			
Class	Subclass	Date	Examiner
709	229, 217	01/05/2007	JC
473	29	01/05/2007	JC
725	6	01/05/2007	JC

SEARCH NOTES		
Search Notes	Date	Examiner
EAST, US Patent, USPGPUB, DERWENT, JPO, EPO, IBM DB	01/05/2007	JC
101 CONSULTATION SPE W. VAUGHN	01/05/2007	JC
NPL GOOGLE SEARCH, IEEE XPlore	01/05/2007	JC
EIC FAST AND FOCUS SEARCH- search specialist Alyson Dill	01/05/2007	JC
consulted William Vaughn-RCE	05/21/2007	JC
EIC FAST AND FOCUS SEARCH-search specialist Byron Mimms	10/24/2007	JC
UPDATED SEARCH	10/27/2007	JC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
709	229,217	10/27/2007	JC
473	29	10/27/2007	JC
725	6	10/27/2007	JC